



Attorney Docket: 3319.3A (02US2)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: James W. Overbeck  
Serial No: 10/034,620  
Filed: December 27, 2001  
For: WIDE FIELD OF VIEW AND HIGH SPEED SCANNING MICROSCOPY

Examiner: T.Q. Nguyen  
Art Unit: 2872

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE**

In Response to the Office Action dated September 17, 2004, Applicant amends this application as follows: